Issue Classification



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ı	Application/Control No.	Applicant(s)/Patent Under Reexamination							
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ı	09466627	LO ET AL.							
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ı	Examiner	Art Unit							
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ı	Maikhanh Nguyen	2176							

ORIGINAL								INTERNATIONAL CLASSIFICATION								
CLASS SUBCLASS					CLAIMED						NON-CLAIMED					
715 234			G	0	6	F	17 / 00 (2006.01.01)									
CROSS REFERENCE(S)					G	0	6	F	7 / 00 (2006.01.01)							
CLASS SUBCLASS (ONE SUBCLASS PER BLOCK)				CK)												
715	230	713														
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	Claims renumbered in the same order as presented by applicant							СР	A [] T.D.	☐ R.1.47				
Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original
1	1		17		33		49		65		81	12	97		
	2		18	11	34		50		66		82	18	98		
	3	4	19		35		51		67		83		99		
	4		20		36		52		68	16	84		100		
	5	5	21	13	37		53		69		85				
	6	6	22		38		54		70		86				
2	7		23		39		55		71	17	87				
	8		24	14	40		56		72		88				
	9	7	25		41		57		73		89				
	10		26		42		58		74	3	90				
	11	8	27	15	43		59		75		91				
	12	9	28		44		60		76		92				
	13		29		45		61		77		93				
	14		30		46		62		78		94				
	15	10	31		47		63		79		95				
	16		32		48		64		80		96				

/Maikhanh Nguyen/ Examiner.Art Unit 2176	09/10/08	Total Claims Allowed:			
(Assistant Examiner)	(Date)				
/Doug Hutton/ Supervisory Patent Examiner, Technology Center 2100	9/15/08	O.G. Print Claim(s)	O.G. Print Figure		
(Primary Examiner)	(Date)	1	6B		

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